

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit	2858	Page 1 of 1
Jeff Natalini				

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	B	US-6,011,404	01-2000	Ma et al.	324/765
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	M	US-			

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**NON-PATENT DOCUMENTS**

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	U	Yoshitake et al. "Measurement of work function change with surface segregation of substate element on a deposited film" May 1999. Applied Surface Science Volume 146, Issues 1-4, pgs 97-100.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.